Search Notes



Application/Control No.	

Applicant(s)/Patent under Reexamination

10/028,842

Examiner
Isaac M. Woo

FRENCH ET AL.

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	SEAR	CHED	
Class	Subclass	Date	Examiner
707	1-10	7/5/2005	iw
707	100-104.1	7/5/2005	IW
707	200-206	7/5/2005	IW
717	168-173	7/5/2005	IW
709	204-207	7/5/5	IW
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INT	ERFERENC	E SEARCH	IED
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH NOT (INCLUDING SEARCH	STRATEGY)
	DATE	EXMR
EAST (USPAT, USPG-PUB, EPO, JPO, DERWENT, IBM_TDB), IEEE, ACM	7/5/05	IW